RIE3 – SPTS Pegasus Operation Log

Date m/d/y	User Name	Recipe Name	Sample Size	# of Samples	Etch Depth (μm)	Cycle Times Dep / Etch (sec)	Total Etch Time	Total Cycles	Critical Feature Size (μm)	Exposed Si (%)	Results & Comments
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Revision 1
K. Bryson
11/24/10